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TABLE OF CONTENTS

LARGE PERSISTENT PHOTOCONDUCTIVITY IN STRONTIUM TITANATE AT ROOM TEMPERATURE	1
<i>V. Poole, J. Dashdorj, M. Zvanut, M. McCluskey</i>	
ELECTRICAL CHARACTERISTICS OF RF SPUTTERED ZNO/HFO₂ INTERFACES IN TRANSPARENT THIN FILM TRANSISTORS	7
<i>P. Thapaliya, W. Lu, R. Jha</i>	
EFFECTS OF ELECTRICAL STRESS AND HIGH-ENERGY ELECTRON IRRADIATION ON THE INGaP/GaAs HETEROJUNCTION PHOTOTRANSISTOR	13
<i>P. Than, K. Uchida, T. Makino, T. Ohshima, S. Nozaki</i>	
SPACE ENVIRONMENTS AND EFFECTS ON CIGS SOLAR CELLS AND MODULES	20
<i>S. Kawakita, M. Imaizumi, H. Kusawake</i>	
TEMPERATURE INDUCED DEGRADATION OF InAlGaN MULTIPLE-QUANTUM WELL UV-B LEDs	27
<i>J. Glaab, C. Ploch, R. Kelz, C. Stolmacker, M. Lapeyrade, N. Ploch, J. Rass, T. Kolbe, S. Einfeldt, F. Mehnke, C. Kuhn, T. Wernicke, M. Weyers, M. Kneissl</i>	
THE INFLUENCE OF THERMAL TREATMENT ON MONOCRYSTALLINE CZT AND TELLURIUM INCLUSIONS	34
<i>J. Lassiter, C. Payton, M. Jackson, S. Uba, C. Muntele, S. Babalola</i>	
RELIABILITY DETECTION OF PROCESS-INDUCED METALLIZATION DEFECTS IN GaAs DEVICES	40
<i>S. Kilgore</i>	
PHYSICAL MECHANISMS AFFECTING THE RELIABILITY OF GaN- BASED HIGH ELECTRON MOBILITY TRANSISTORS	46
<i>R. Schrimpf, D. Fleetwood, S. Pantelides, Y. Puzyrev, S. Mukherjee, R. Reed, J. Speck, U. Mishra</i>	
WHITE BEAM X-RAY DIFFRACTION TOPOGRAPHY (WBXDT) STUDIES OF BRIDGMAN GROWN CdZnTe CRYSTALS	54
<i>S. Babalola, S. Uba, A. Hossain, G. Camarda, R. James, T. Montgomery</i>	
IMPACT OF LOW DOSE GAMMA IRRADIATION ON ELECTRONIC CARRIER TRANSPORT IN InGaP/GaN HIGH ELECTRON MOBILITY TRANSISTORS	60
<i>A. Yadav, E. Flitsiyan, L. Chernyak, F. Ren, S. Pearton, J. Johnson, I. Lubomirsky</i>	
RELIABILITY AND DEGRADATION MECHANISMS IN HIGH POWER BROAD-AREA InGaAs-AlGaAs STRAINED QUANTUM WELL LASERS	66
<i>Y. Sin, N. Presser, S. Lalumondiere, M. Brodie, Z. Lingley, N. Ives, B. Foran, W. Lotshaw, S. Moss</i>	

CHARACTERIZATION OF EXTENDED DEFECTS OBSERVED IN CADMIUM ZINC TELLURIDE (CZT) CRYSTAL	75
<i>S. Uba, S. Babalola</i>	
ORDERING OF INGAAS QUANTUM DOTS GROWN BY MOLECULAR BEAM EPITAXY UNDER AS₂ GAS FLUX.....	81
<i>M. Benamara, Y. Mazur, P. Lytvyn, M. Ware, V. Dorogan, X. Hu, L. Souza, E. Marega, M. Theodores, G. Marques, G. Salamo</i>	
RELEVANCE OF THREADING DISLOCATIONS FOR THE THERMAL OXIDATION OF GAN (0001).....	87
<i>M. Reiner, C. Koller, K. Pekoll, R. Pietschnig, C. Ostermaier</i>	
MECHANICAL AND OPTICAL PROPERTIES CHARACTERIZATION OF C-PLANE (0001) AND M-PLANE 10 10) GAN BY NANOINDENTATION AND LUMINESCENCE.....	93
<i>T. Yokogawa, M. Fujikane, S. Nagao, R. Nowak</i>	
STUDY OF PHOTOLUMINESCENCE PROPERTIES OF CU_xO THIN FILMS PREPARED BY REACTIVE RADIO FREQUENCY MAGNETRON SPUTTERING.....	103
<i>J. Gan, A. Galeckas, V. Venkatachalapathy, H. Riise, B. Svensson, E. Monakhov</i>	
RELIABILITY STUDY OF ORGANIC LIGHT-EMITTING DIODES BY CONTINUOUS-WAVE AND PULSED CURRENT STRESSING	110
<i>X. Li, R. Acharya, Y. Zhang, X. Cao</i>	
SELECTIVELY NUCLEATED LATERAL CRYSTALLIZATION FOR A LARGE SINGLE-GRAINED PB(ZR,TI)O₃ ON POLYCRYSTALLINE- SILICON THIN-FILM TRANSISTORS FOR SYSTEM-ON-GLASS APPLICATIONS	116
<i>J. Park, S. Joo</i>	
EVOLUTION OF STRUCTURAL AND OPTICAL PROPERTIES ON PIN AND NIP PM-SI:H DEVICES DURING 400 HRS OF LIGHT-SOAKING	123
<i>L. Hamui, P. Cabarrocas, G. Santana</i>	
MODELING OF CZT RESPONSE TO GAMMA PHOTONS USING MCNP AND GARFIELD.....	130
<i>J. Lassiter, R. Robinson, L. Williams, S. Babalola, C. Muntele</i>	
Author Index	